

IGBT

TRENCHSTOP[™] IGBT4 Low Power Chip IGC11T120T8L

Data Sheet

Industrial Power Control



Table of Contents

Features and Applications	3
Mechanical Parameters	3
Maximum Ratings	4
Static and Electrical Characteristics	4
Further Electrical Characteristics	5
Chip Drawing	6
Revision History	7
Relevant Application Notes	7
Legal Disclaimer	
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TRENCHSTOP[™] IGBT4 Low Power Chip

Features:

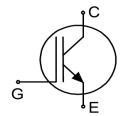
- 1200V trench & field stop technology
- Low switching losses
- Positive temperature coefficient
- Easy paralleling

Recommended for:

• Low / medium power modules

Applications:

Low / medium power drives



Rev. 2.1, 20.08.2015

Chip Type	V _{CE}	/ Cn ¹	Die Size	Package
IGC11T120T8L	1200V	8A	3.48mm x 3.19mm	Sawn on foil

Mechanical Parameters

Die size		3.48 x 3.19		
Emitter pad size		See chip drawing	2	
Gate pad size		0.608 x 0.608	mm ²	
Area total		11.1		
Thickness		115	μm	
Wafer size		200	mm	
Maximum possible ch	ips per wafer	2408		
Passivation frontside		Photoimide		
Pad metal		3200nm AlSiCu		
Backside metal		Ni Ag – system To achieve a reliable solder connection it is strongly recommended not to consume the Ni layer completely during production process		
Die bond		Electrically conductive epoxy glue and soft solder		
Wire bond		Al, ≤500μm		
Reject ink dot size		Ø 0.65mm; max. 1.2mm		
Storago onvironment	for original and sealed MBB bags	Ambient atmosphere air, temperature 17°C – 25°C, <6 months		
Storage environment	for open MBB bags	Acc. to IEC62258-3: atmosphere >99% Nitrogen or inert gas, humidity <25%RH, temperature 17°C – 25°C, <6 months		

¹ Nominal collector current at TC = 100°C assuming chip assembly in TO-247 package.

L7613P, L7613V 3



Maximum Ratings

Parameter	Symbol	Value	Unit
Collector-emitter voltage, T_{vj} =25°C	V _{CE}	1200	V
DC collector current, limited by $T_{\rm vj\;max}^{\;2}$	I _C	-	Α
Pulsed collector current, $t_{\rm p}$ limited by $T_{\rm vjmax}^{~3}$	I _{C,puls}	24	Α
Gate-emitter voltage	V_{GE}	±20	V
Operating junction temperature	$T_{\rm vj}$	-40 +175	°C
Short circuit data $^{3/4}$ V_{GE} =15V, V_{CC} =800V, T_{vj} =150°C	t _{sc}	10	μs

Static Characteristics (tested on wafer), T_{vi}=25°C

Parameter	Symbol	Conditions	Value			Unit	
rai ailletei	Syllibol	Symbol Conditions		typ.	max.		
Collector-emitter breakdown voltage	$V_{(BR)CES}$	$V_{\rm GE}$ =0V, $I_{\rm C}$ =0.5mA	1200	-	-		
Collector-emitter saturation voltage	V _{CEsat}	V _{GE} =15V, I _C =8A	1.58	1.85	2.07	V	
Gate-emitter threshold voltage	$V_{\rm GE(th)}$	$I_{\rm C} = 0.15 {\rm mA}, \ V_{\rm GE} = V_{\rm CE}$	5.3	5.8	6.3		
Zero gate voltage collector current	I _{CES}	$V_{\text{CE}} = 1200 \text{V}, \ V_{\text{GE}} = 0 \text{V}$	-	-	1	μA	
Gate-emitter leakage current	I _{GES}	$V_{CE} = 0V, V_{GE} = 20V$	ı	ı	120	nA	
Integrated gate resistor	r _G			none		Ω	

Electrical Characteristics ³

Parameter	Symbol	Conditions	Value			Unit
raiailietei			min.	typ.	max.	Onit
Collector-emitter saturation voltage	V_{CEsat}	$V_{\text{GE}} = 15 \text{V}, I_{\text{C}} = 8 \text{A}, \ T_{\text{vj}} = 150 ^{\circ} \text{C}$	-	2.25	-	V
Input capacitance	C _{ies}	V _{CE} =25V,	-	490	1	nE
Reverse transfer capacitance	C _{res}	V_{GE} =0V, f =1MHz T_{vj} =25°C	-	30	-	pF

² Depending on thermal properties of assembly.

³ Not subject to production test - verified by design/characterization.

⁴ Allowed number of short circuits: <1000; time between short circuits: >1s.



Further Electrical Characteristics

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

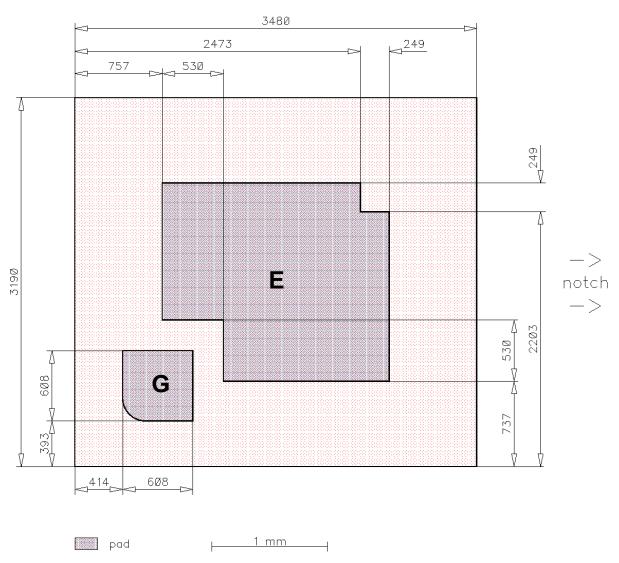
Application example	-	_	
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L7613P, L7613V 5 Rev. 2.1, 20.08.2015



Chip Drawing





 $\mathbf{E} = \mathsf{Emitter}$

 $\mathbf{G} = \mathsf{Gate}$



Bare Die Product Specifics

Test coverage at wafer level cannot cover all application conditions. Therefore it is recommended to test all characteristics which are relevant for the application at package level, including RBSOA and SCSOA.

Description

AQL 0.65 for visual inspection according to failure catalogue

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Revision History

Revision	Subjects (major changes since last revision)	Date
2.0	Final data sheet	18.02.2015
2.1	Update disclaimer	20.08.2015

Relevant Application Notes



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